Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/711,518	YEH, TING-KUN
Examiner	Art Unit
Arpan P. Savla	2185

Arpan P. Savla

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR)
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